APPLICANT (PTO-1449)				ATTY. DOCKET NO. HI-0075		APPLN. SERIAL NO. 10/092,545		
				APPLICANT(S) So Young BAE, Sung Bae JUN and Kyoung Ro YOON				
				FILING DATE March 8, 2002		GROUP <b>2611</b>		
& IRADE		U	.S. PATENT DO	CUMENTS				
EXAMINER'S INITIALS			*INVEN	*INVENTOR NAME		SUBCLASS	FiLI DA	
			<u> </u>					
					F	ECE!	<del>/E</del> E	<del>)</del>
						APR 18	2003	
					Technology Center 2600			
						3,		
					<u></u>			
	*DATENT	U.S. PATE	NT APPLICATI	ON PUBLICATIO	NS	<del></del>		
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APF	PLICANT	CLASS	SUBCLASS		
			U.S. PATENT APP	PLICATIONS		I		-
	*APPLN. NO.	*FILING DATE	*IN\	/ENTOR	CLASS	SUBCLASS		
				-				
FOREIGN PATENT DOCUMENTS								
EXAMINER'S INITIALS	PATENT NO.	DATE	со	UNTRY	CLASS	SUBCLASS	Trans Yes	ation No
DR	WO 98/34182	08-06-98	WIPO				Х	
				<del> </del>				
-	<u>-</u>							
ОТН	ER ART (Includi	ng Author, Ti	tle, Date, Pertin	ent Pages, Publishe	r, Place of	Publication, I	Etc.)	
						<del></del>	·	
EXAMINER Definition				PATE CONSIDERED 7 – 12 – 06				

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.